

Industrial 3D NAND M.2 2280 SSD

MDC3K0E SERIES

| SATA III | 6.0 Gbit/s | | |
|------------|------------|--|--|
| SI C Cacho | 3D NAND | | |



PRODUCT FEATURES

- High-Quality 3D NAND Flash Technology
- Global Wear Leveling and Early weak block retirement
- TRIM, NCQ, ATA Security Feature Set supported
- Lifetime Enhancements

Direct-to-TLC and SLC Cache enhancement to ensure the optimized WAF

Block/Page RAID function to ensure data recovery

- Reliable Industrial-grade circuit design and complete protection design with OVP, OCP, surge rejection, and Short protection.
- Power shielding firmware architecture to ensure power failure resilience
- AES256 Encryption and TCG Opal 2.0 compliant (by request)
- SP SMART Toolbox
- SP SMART Embedded and SMART IoT service (by request)
- Native Command Queuing up to 32 commands
- Garbage collection and TRIM Data Set Management command
- Global wear leveling algorithm evens program/erase count

PRODUCT SUMMARY

Capacities: 64GB, 128GB, 256GB, 512GB, 1TB

Form Factor: M.2 2280 SATA Solid State Drive (80 mm x 22 mm x 3.5 mm)

• Compliance: SATA Revision 3.1 - 6 Gbit/s (3 Gbit/s and 1.5 Gbit/s backward compatible)

Command Sets: Supports ATA/ATAPI-8 and ACS-2

Performance : (estimated)

| | 64GB | 128GB | 256GB | 512GB | 1TB |
|------------------------------|-------|-------|-------|-------|-------|
| Sequential Read (MB/s Max.) | 480 | 540 | 540 | 540 | 540 |
| Sequential Write (MB/s Max.) | 280 | 230 | 460 | 520 | 510 |
| Random 4K Read (IOPS Max.) | 20000 | 17000 | 28000 | 29000 | 28000 |
| Random 4K Write (IOPS Max.) | 49000 | 53000 | 82000 | 86000 | 84000 |

^{*} Actual performance may vary based on the specific model and capacity

Operating Temperature Range :

Normal: 0°C to 70°C

Storage Temperature Range: -55°C to 95°C

Operating Voltage : 3.3V ± 10%
Power Consumption : (estimated)

| (Unit: mA) | 64GB | 128GB | 256GB | 512GB | 1TB | |
|--------------|-------|-------|-------|-------|-------|--|
| Read (Max.) | 470 | 470 | 480 | 500 | 510 | |
| Write (Max.) | 425 | 400 | 525 | 570 | 580 | |
| Idle(Avg.) | < 130 | < 130 | < 130 | < 130 | < 130 | |

^{*} Actual value may vary based on the specific model and capacity

- Data Retention @40 °C: 10 Years @ Life Begin; 1 Year @ Life End
- Endurance in Tera Bytes Written (TBW): (Unit: TB) (estimated)

| Workload | 64GB | 128GB | 256GB | 512GB | 1TB |
|------------|------|-------|-------|-------|------|
| Sequential | 91 | 182 | 364 | 728 | 1456 |
| Enterprise | 25 | 51 | 101 | 202 | 404 |

TBW is estimated by formula TBW = (Capacity x PE Cycles) x (1+OP) x (WLE) / (WAF)

OP (Over Provision) = (Physical Capacity / Logical Capacity)-1

WAF = Write Amplification Factor

WLE = Wear Leveling Efficiency could be different depended on the workload or usage containing data size and access rate.

Sequential workload: Sequential write workload which is generated by VDBENCH script and tested by VDBENCH

Enterprise workload: Follow JESD219A enterprise workload which is generated by VDBENCH script and tested by VDBENCH.

Mechanical (IEC-60068):

Vibration: 15G, 10 ~ 2001Hz

Drop: 76cm

Shock: 1,500G@0.6ms

- LDPC ECC engine and Block/Page RAID to ensure reliable 3K PE cycles
- Mean Time Between Failure: > 2,000,000 hours
- Data Reliability: Non-recover Read (UBER) ≤10⁻¹⁶
- Serious quality control and assurance

100% NAND Flash screening

High endurance product design with 3D NAND product offerings

Implement high/low temperature dynamic burn-in in each lot production to monitor production quality to meet design specification

Reliability criteria compliant with international standards IEC-60068/61000

